


Serial No. To be assigned

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Petersen, et al	Examiner:	To be assigned
Serial No.:	To be assigned	Group Art Unit:	To be assigned
Filed:	9/30/03	Docket No.:	00900.0302-US-C1
Title:	MULTI-POINT PROBE		

<p>CERTIFICATE UNDER 37 C.F.R. 1.10: 'Express Mail' mailing number: <u>EV314776906US</u> Date of Deposit: <u>September 30, 2003</u> The undersigned hereby certifies that this Transmittal Letter and the paper or fee, as described herein, are being deposited with the United States Postal Service 'Express Mail Post Office To Addressee' service under 37 CFR 1.10 and is addressed to the Commissioner for Patents, Alexandria, VA 22313-1450. By:  Brenda Jurgens</p>

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97(b)

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Applicant(s) respectfully submit(s) the items of information on the enclosed Form 1449 for the attention of the Examiner in the above-identified application.

This Information Disclosure Statement is being filed within three months of the filing of a national application other than a continued prosecution application under 37 C.F.R. 1.53(d); within three months of the date of entry of the national stage as set forth in 37 C.F.R. 1.491 in an international application; before the mailing date of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 C.F.R. 1.114. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

A copy of each document or other information listed on the enclosed Form 1449 is enclosed in accordance with 37 C.F.R. §1.98(a)(2) and/or a copy of each document is not provided because it was previously cited by or submitted to the U.S. Patent and Trademark Office in a parent application in accordance with 37 C.F.R. §1.98(d).

No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§102 and 103. In addition, Applicant(s) do(es) not represent that a reference has been thoroughly reviewed or that any relevance of any portion of a reference is intended, and reserve the right to establish otherwise under 37 C.F.R. §1.131 or others.

Consideration of the items listed is respectfully requested. According to M.P.E.P. §609, Applicant(s) request(s) that the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

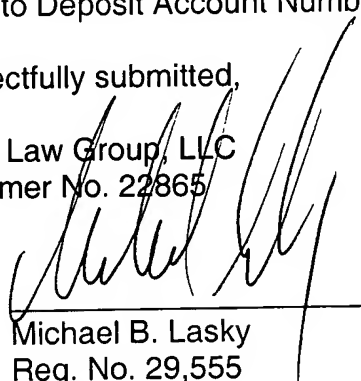
Authorization is hereby given to charge any additional fees or credit any overpayments that may be deemed necessary to Deposit Account Number 50-1038.

Respectfully submitted,

Altera Law Group, LLC
Customer No. 22865

Date: September 30, 2003

By:



Michael B. Lasky
Reg. No. 29,555
MBL/blj

INFORMATION DISCLOSURE STATEMENT

PTO Form 1449

Docket Number
900.302USW1

Serial Number
09/750645

Applicant(s)
Petersen, et al.

Filing Date
28 December 2000

Group Art Unit
~~2858~~ 2829

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS

RK	Koops, et al., "Constructive three-dimensional lithography with electron-beam induced deposition for quantum effect devices", <u>Journal of Vacuum Science & Technology B (Microelectronics Processing and Phenomena)</u> , Vol. 11, No. 6, pp. 2286-2289 (November/December 1993).
RK	Koops, et al., "Conductive dots, wires, and supertips for field electron emitters produced by electron-beam induced deposition on samples having increased temperature", <u>Journal of Vacuum Science & Technology B (Microelectronics Processing and Phenomena)</u> , Vol. 14, No. 6, pp. 4105-4109 (November/December 1996).
RK	Niu, et al., "Double-tip scanning tunneling microscope for surface analysis", <u>Physical Review B</u> , Vol. 51, No. 8, pp. 5502-5505 (February 15, 1995).
RK	Shi, et al., "New method of calculating the correction factors for the measurement of sheet resistivity of a square sample with a square four-point probe", <u>Rev. Sci. Instrum.</u> , Vol. 68, No. 4, pp. 1814-1817 (April 1997).
RK	Smits, "Measurement of Sheet Resistivities with the Four-Point Probe", <u>The Bell System Technical Journal</u> , Vol. 37, pp. 711-718 (May 1958).

Examiner:

Date Considered: 3-14-03

part of paper #7



APR 23 2001

INFORMATION DISCLOSURE STATEMENT

PTO Form 1449

Docket Number
900.302USW1Serial Number
09/750645Applicant(s)
Petersen, et al.Filing Date
28 December 2000

Group Art Unit

~~2858~~ 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE (IF APPROPRIATE)
<i>RK</i>		5613861	03/25/97	Smith, et al.	—	—	
<i>RK</i>		5557214	09/17/96	Barnett	—	—	
<i>RK</i>		5540958	07/30/96	Bothra, et al.	—	—	
<i>RK</i>		5475318	12/12/95	Marcus, et al.	—	—	
<i>RK</i>		5171992	12/15/92	Clabes, et al.	—	—	
<i>RK</i>		5347226	09/13/94	Bachmann, et al.	—	—	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
<i>RK</i>		WO 94/11745	05/26/94	WIPO				
<i>RK</i>		EP 0 899 538	03/03/99	European Patent Office				
<i>RK</i>		EP 0 466 274	01/15/92	European Patent Office				
<i>RK</i>		EP 0 299 875	01/18/89	European Patent Office				
<i>RK</i>		DE 196 48 475	06/05/97	Germany				
<i>RK</i>		DE 43 01 420	06/24/93	Germany				
<i>RK</i>		8-15318	01/19/96	Japan				
<i>RK</i>		07199219	08/04/95	Japan			Abstract	
<i>RK</i>		01147374	06/09/89	Japan			Abstract	

OTHER DOCUMENTS

<i>RK</i>		Fujii, et al., "Micropattern measurement with an atomic force microscope", <u>Journal of Vacuum Science & Technology: Part B</u> , Vol. 9, No. 2, pp. 666-669 (March/April 1991).
<i>RK</i>		Lee, et al., "High-Density Silicon Microprobe Arrays for LCD Pixel Inspection", <u>Institute of Electrical and Electronics Engineers</u> , pp. 429-434 (February 11, 1996).
<i>RK</i>		Hong, et al., "Design and Fabrication of a Monolithic High-Density Probe Card for High-Frequency On-Water Testing", <u>Institute of Electrical and Electronics Engineers</u> , pp. 289-292 (December 3, 1989).
<i>RK</i>		International Search Report for PCT/DK99/00391 (July 8, 1999)
		(completion date January 12, 2000)

Examiner:

Date Considered:

3-14-03

part of paper #6

Notice of References Cited

Application/Control No.

09/750,645

Applicant(s)/Patent Under
Reexamination
PETERSEN ET AL.

Examiner

Russell M Kobert

Art Unit

2829

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,520,314	05-1985	Asch et al.	324/762
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.